

## ST4000

# Specification & Features

▷ ST4000DLX

<b>Measurement range</b>	100 Å ~ 35 μm (Depends on film)
<b>Measurement speed</b>	1~2 sec/site
<b>Stage size</b>	200mm X 200mm(8") 300mm X 300mm(12")
<b>Measuring sample size</b>	≤ 8", 12"(option)
<b>Spot size</b>	40 μm/20 μm, 4 μm(option)
<b>Measurement principle</b>	Reflectometer
<b>Measurement method</b>	Non-contact
<b>Type</b>	Manual
<b>Dimension</b>	500 x 610 x 640 mm
<b>Weight</b>	45Kg
<b>Focus</b>	Coaxial coarse and fine focus control
<b>Illumination</b>	12v 100w Halogen lamp



<b>Option</b>	Reference sample CCD Camera Transmittance module Auto Z axis movement (lens)
<b>Features</b>	Fast Measurement & Easy Operation Non-contact & Non-destructive Superb Repeatability & Reproducibility Windows based user-friendly interface Print function of each view & data saving
<b>Application</b>	All capability of ST2000 & more precision measurement Intended for wafer measurement & OLED